

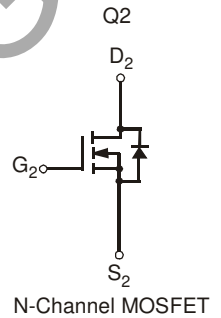
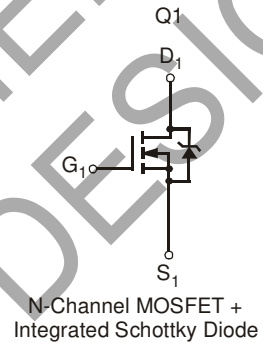
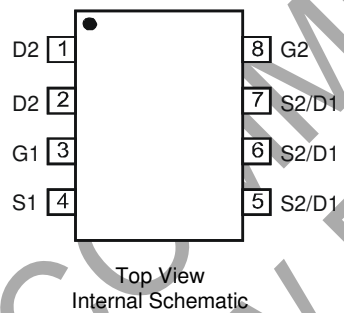
ASYMMETRIC DUAL N-CHANNEL ENHANCEMENT MODE MOSFET

Features

- DIOFET Utilizes a Unique Patented Process to Monolithically Integrate a MOSFET and a Schottky in a Single die to Deliver:
 - Low $R_{DS(on)}$ —Minimizes Conduction Loss
 - Low V_{SD} —Reduces Losses due to Body Diode Construction
 - Low Q_{rr} —Lower Q_{rr} of Integrated Schottky Reduces Body Diode Switching Losses
 - Low Gate Capacitance (Q_g/Q_{gs}) Ratio—Reduces Risk of Shoot-Through or Cross Conduction Currents at High Frequencies
 - Avalanche Rugged— I_{AR} and E_{AR} Rated
- **Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)**
- **Halogen and Antimony Free. "Green" Device (Note 3)**
- **Qualified to AEC-Q101 Standards for High Reliability**

Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- WTSSOP-16EP (Type DX) Eight: 0.072 grams (Approximate)

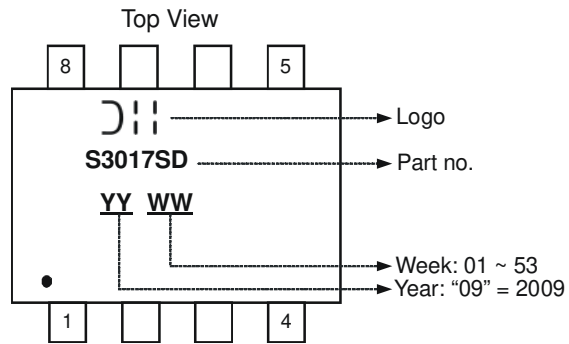


Ordering Information (Note 3)

Part Number	Case	Packaging
DMS3017SSD-13	SO-8	2500/Tape & Reel

- Notes:
1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant.
 2. See <https://www.diodes.com/quality/lead-free/> for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free
 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
 4. For packaging details, go to our website at <http://www.diodes.com/>.

Marking Information



Maximum Ratings – Q1 @TA = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	± 20	V
Continuous Drain Current (Note 4) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	8.0	A
		$T_A = 70^\circ C$		6.5	
Continuous Drain Current (Note 5) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	10	A
		$T_A = 70^\circ C$		7.8	
Continuous Drain Current (Note 5) $V_{GS} = 4.5V$	Steady State	$T_A = 25^\circ C$	I_D	8.7	A
		$T_A = 70^\circ C$		7.0	
Pulsed Drain Current (Note 6)			I_{DM}	60	A
Avalanche Current (Notes 6 & 7)			I_{AR}	16	A
Repetitive Avalanche Energy (Notes 6 & 7) $L = 0.1mH$			E_{AR}	12.8	mJ

Maximum Ratings – Q2 @TA = 25°C unless otherwise specified

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			V_{DSS}	30	V
Gate-Source Voltage			V_{GSS}	± 20	V
Continuous Drain Current (Note 4) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	6.0	A
		$T_A = 70^\circ C$		4.7	
Continuous Drain Current (Note 5) $V_{GS} = 10V$	Steady State	$T_A = 25^\circ C$	I_D	7.2	A
		$T_A = 70^\circ C$		6.0	
Continuous Drain Current (Note 5) $V_{GS} = 4.5V$	Steady State	$T_A = 25^\circ C$	I_D	6.0	A
		$T_A = 70^\circ C$		5.0	
Pulsed Drain Current (Note 6)			I_{DM}	60	A
Avalanche Current (Notes 6 & 7)			I_{AR}	16	A
Repetitive Avalanche Energy (Notes 6 & 7) $L = 0.1mH$			E_{AR}	12.8	mJ

Thermal Characteristics

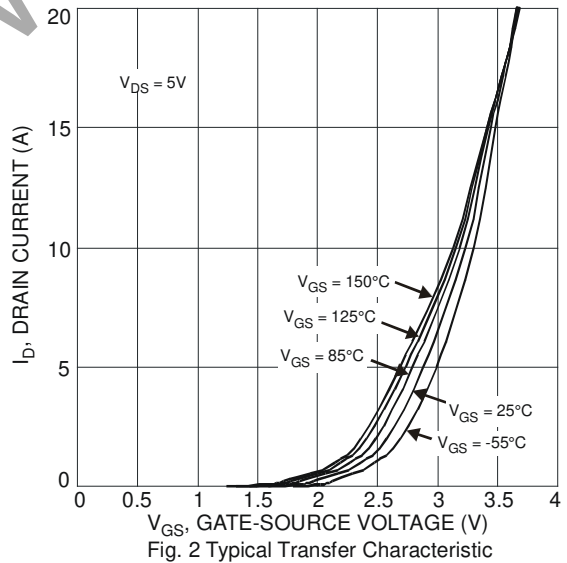
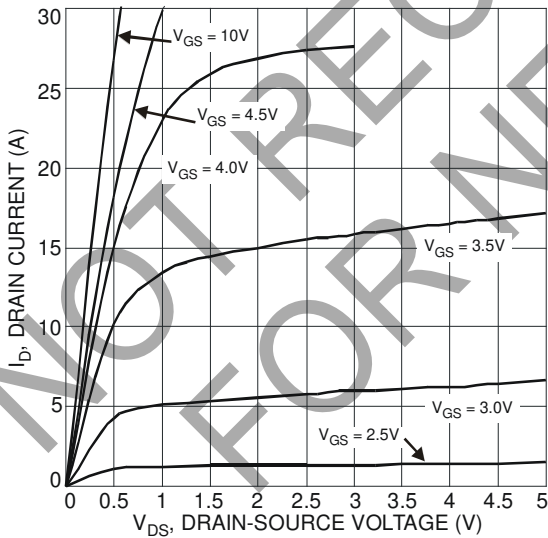
Characteristic	Symbol	Value	Unit
Power Dissipation (Note 4)	P_D	1.19	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ C$ (Note 4)	$R_{\theta JA}$	107	$^\circ C/W$
Power Dissipation (Note 5)	P_D	1.79	W
Thermal Resistance, Junction to Ambient @ $T_A = 25^\circ C$ (Note 5)	$R_{\theta JA}$	70	$^\circ C/W$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ C$

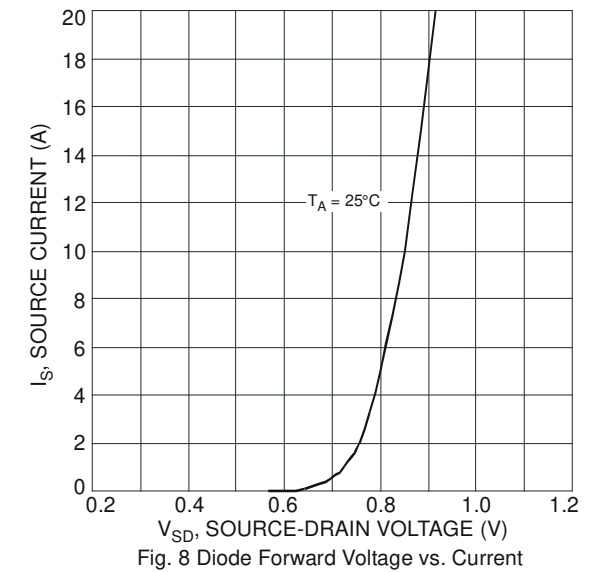
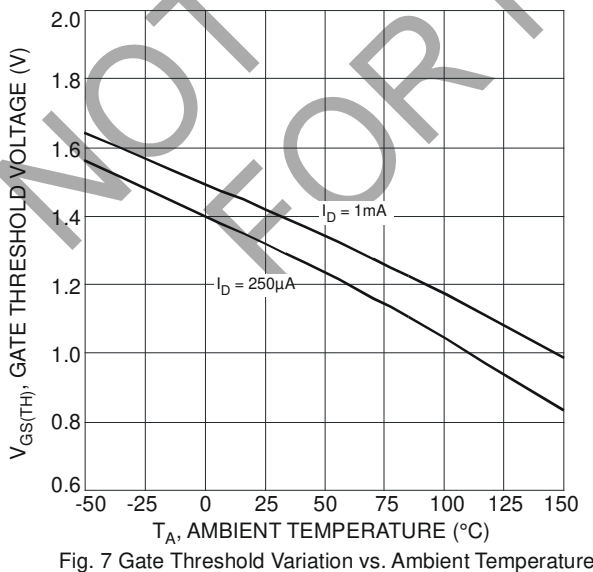
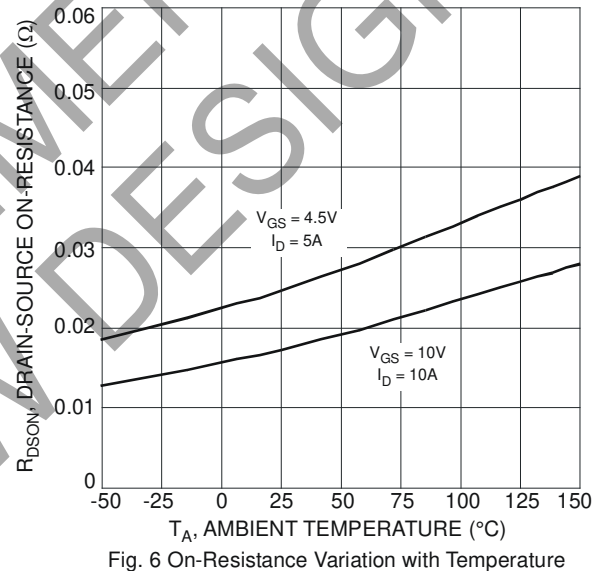
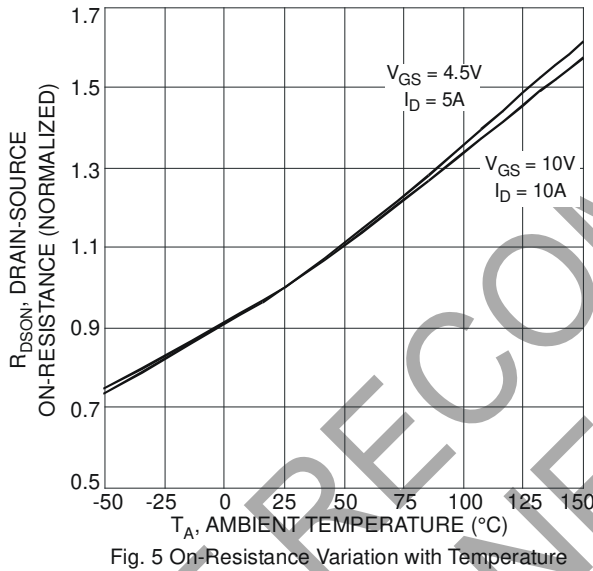
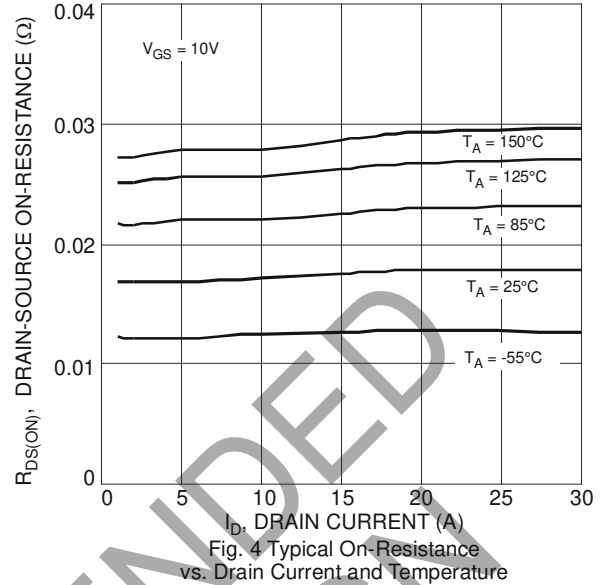
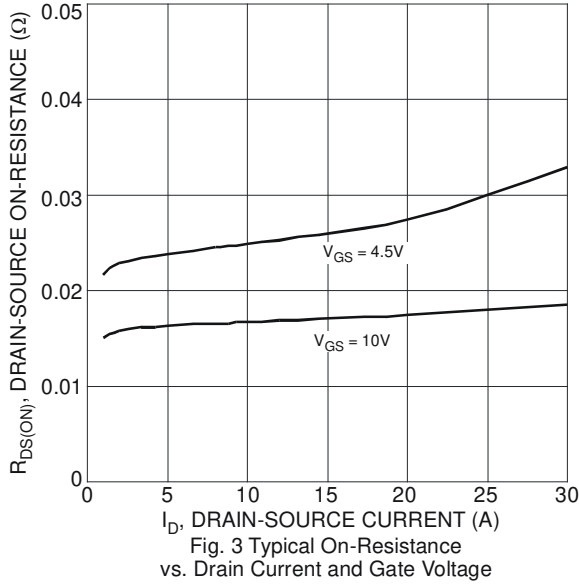
- Notes:
- Device mounted on FR-4 substrate PCB, with minimum recommended pad layout. The value in any given application depends on the user's specific board design. Device contains two active die running at equal power.
 - Device mounted on 1 inch \times 1 inch FR4 PCB with high coverage of single sided 1oz copper, in still air conditions. Device contains two active die running at equal power.
 - Repetitive rating, pulse width limited by junction temperature.
 - I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep $T_J = 25^\circ C$

Electrical Characteristics – Q1 @ T_A = 25°C unless otherwise stated

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	—	—	V	V _{GS} = 0V, I _D = 250μA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	100	μA	V _{DS} = 30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(th)}	1.0	—	2.5	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	8.5	12	mΩ	V _{GS} = 10V, I _D = 9.5A
			9.5	15		V _{GS} = 4.5V, I _D = 8.8A
Forward Transfer Admittance	Y _{fs}	—	18	—	S	V _{DS} = 5V, I _D = 9.5A
Diode Forward Voltage	V _{SD}	—	0.45	0.60	V	V _{GS} = 0V, I _S = 1A
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C _{iss}	—	1276	—	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{oss}	—	160	—		
Reverse Transfer Capacitance	C _{rss}	—	136	—		
Gate Resistance	R _g	—	1.48	2.7	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	14.3	—	nC	V _{DS} = 15V, V _{GS} = 4.5V, I _D = 8.8A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	30.6	—		
Gate-Source Charge	Q _{gs}	—	3.4	—		
Gate-Drain Charge	Q _{gd}	—	4.3	—		
Turn-On Delay Time	t _{D(on)}	—	15.8	—	ns	V _{GS} = 4.5V, V _{DS} = 15V, R _G = 1.8Ω, I _D = 8.8A
Turn-On Rise Time	t _r	—	27.8	—		
Turn-Off Delay Time	t _{D(off)}	—	29.7	—		
Turn-Off Fall Time	t _f	—	13.6	—		

Notes: 8. Short duration pulse test used to minimize self-heating effect.
9. Guaranteed by design. Not subject to production testing.





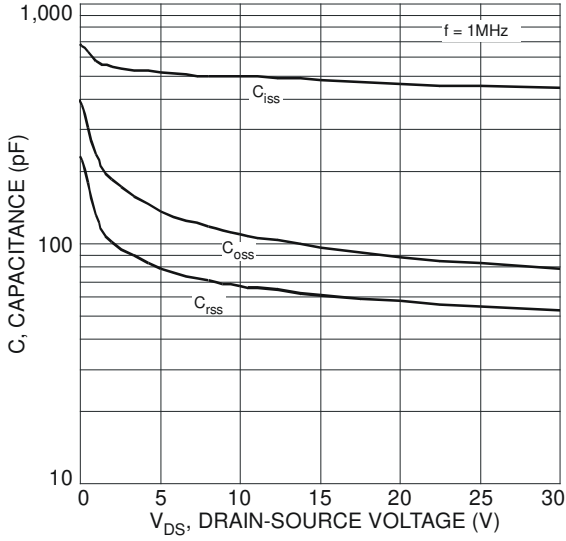


Fig. 9 Typical Total Capacitance

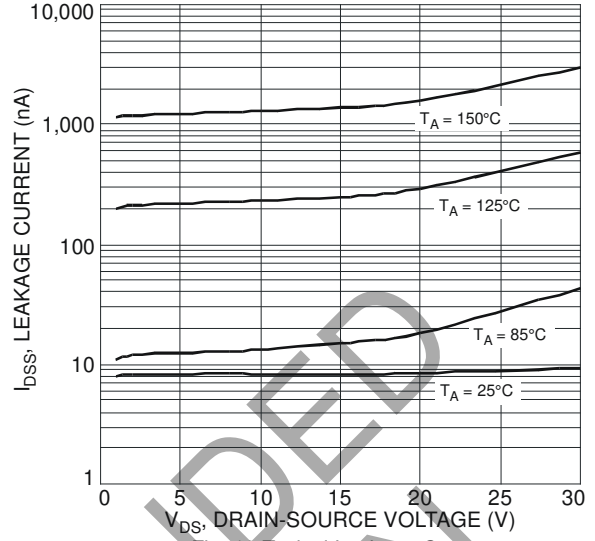


Fig. 10 Typical Leakage Current vs. Drain-Source Voltage

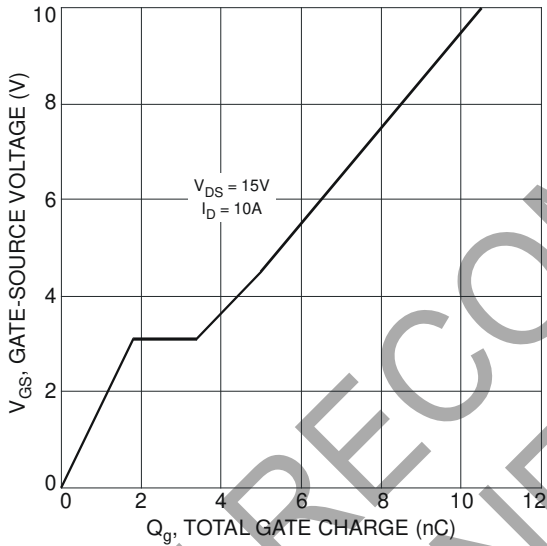


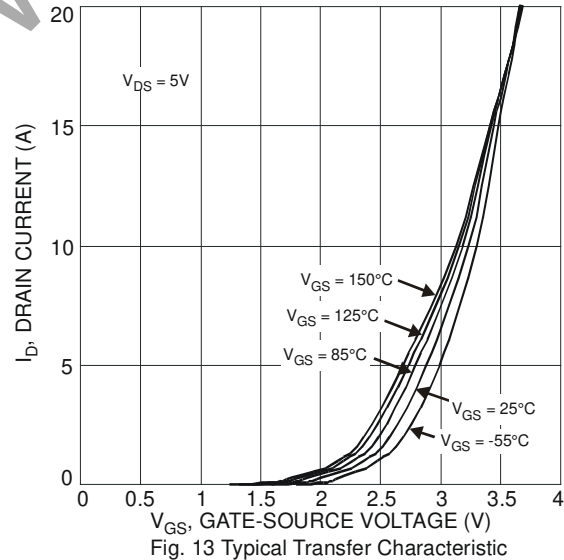
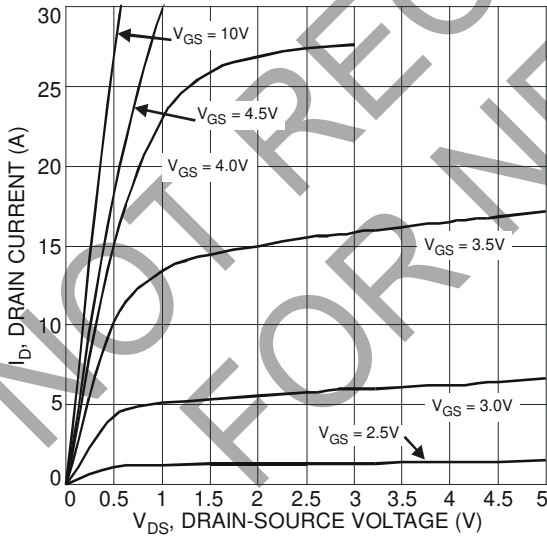
Fig. 11 Gate-Charge Characteristics

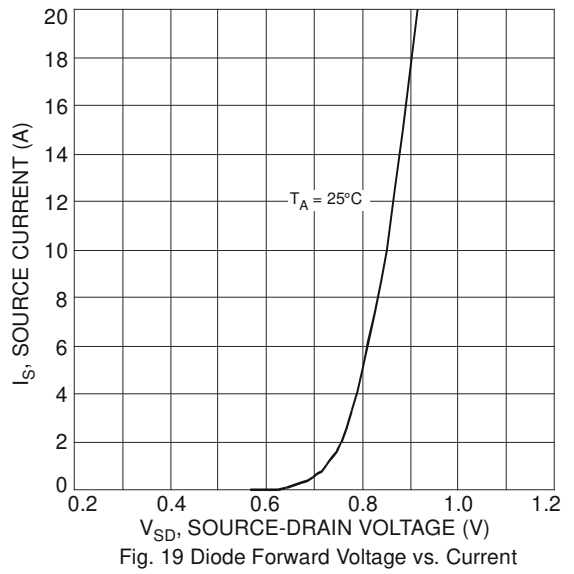
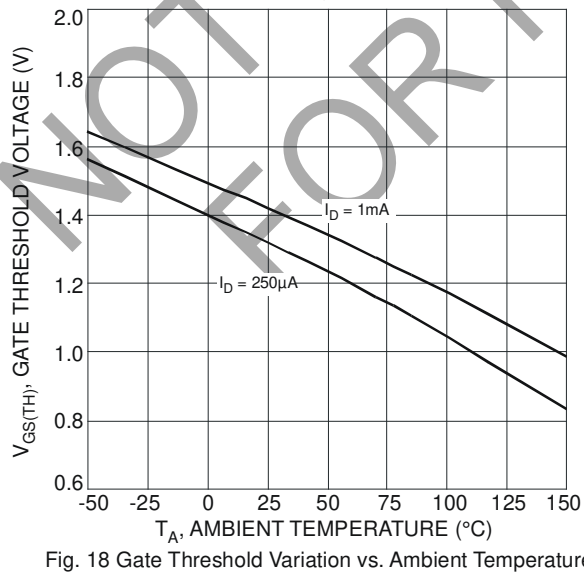
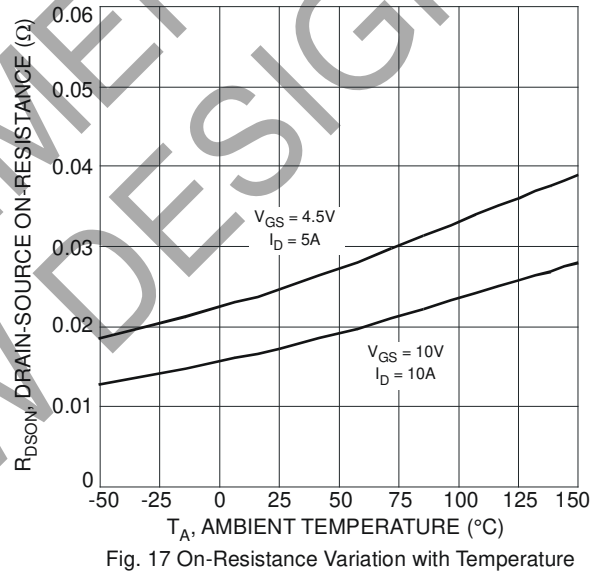
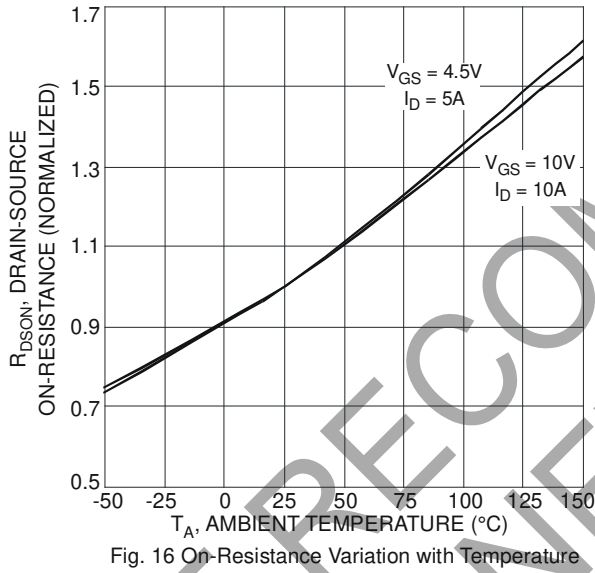
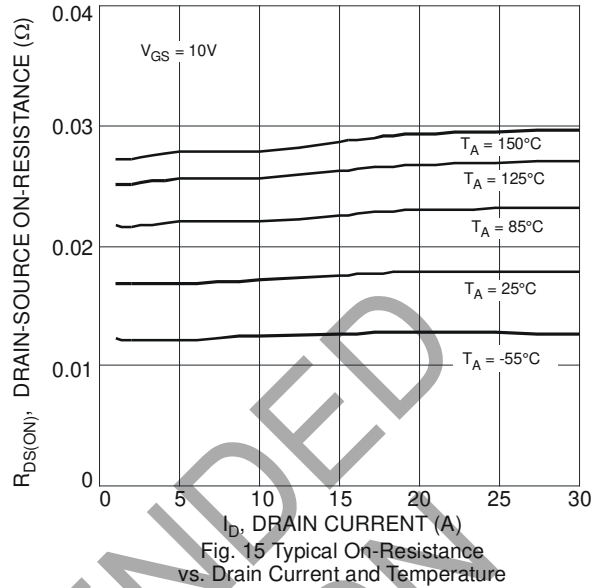
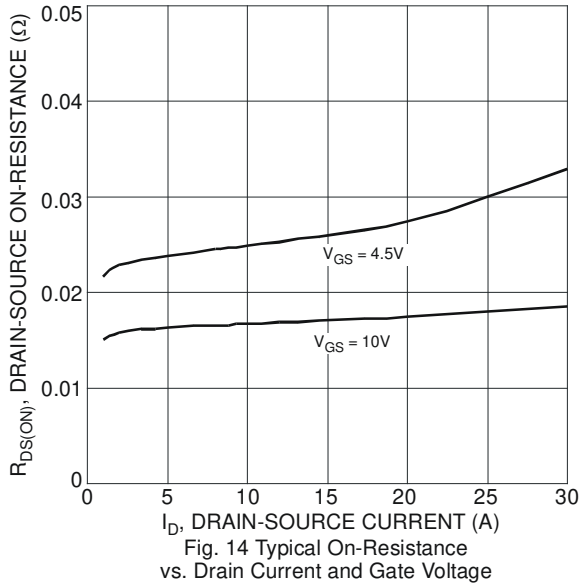
NOT RECOMMENDED FOR NEW DESIGN

Electrical Characteristics – Q2 @ T_A = 25°C unless otherwise stated

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	—	—	V	V _{GS} = 0V, I _D = 1mA
Zero Gate Voltage Drain Current	I _{DSS}	—	—	—	μA	V _{DS} = 30V, V _{GS} = 0V
Gate-Source Leakage	I _{GSS}	—	—	±100	nA	V _{GS} = ±20V, V _{DS} = 0V
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(th)}	1.0	-	2.4	V	V _{DS} = V _{GS} , I _D = 250μA
Static Drain-Source On-Resistance	R _{DS(ON)}	—	15 25	22 32	mΩ	V _{GS} = 10V, I _D = 8.8A V _{GS} = 4.5V, I _D = 7A
Forward Transfer Admittance	Y _{fs}	—	2.5	—	S	V _{DS} = 5V, I _D = 8.8A
Diode Forward Voltage	V _{SD}	—	0.7	1	V	V _{GS} = 0V, I _S = 1A
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	C _{iss}	—	478.9	—	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz
Output Capacitance	C _{oss}	—	96.7	—		
Reverse Transfer Capacitance	C _{rss}	—	61.4	—	Ω	V _{DS} = 0V, V _{GS} = 0V, f = 1MHz
Gate Resistance	R _g	—	1.1	—		
Total Gate Charge (V _{GS} = 4.5V)	Q _g	—	5.0	—	nC	V _{DS} = 15V, V _{GS} = 4.5V, I _D = 10A
Total Gate Charge (V _{GS} = 10V)	Q _g	—	10.5	—		
Gate-Source Charge	Q _{gs}	—	1.8	—	ns	V _{DS} = 15V, V _{GS} = 10V, I _D = 10A
Gate-Drain Charge	Q _{gd}	—	1.6	—		
Turn-On Delay Time	t _{D(on)}	—	2.9	—	ns	V _{GS} = 10V, V _{DS} = 15V, R _G = 3Ω, R _L = 1.5Ω
Turn-On Rise Time	t _r	—	7.9	—		
Turn-Off Delay Time	t _{D(off)}	—	14.6	—		
Turn-Off Fall Time	t _f	—	3.1	—		

Notes: 8. Short duration pulse test used to minimize self-heating effect.
9. Guaranteed by design. Not subject to production testing.





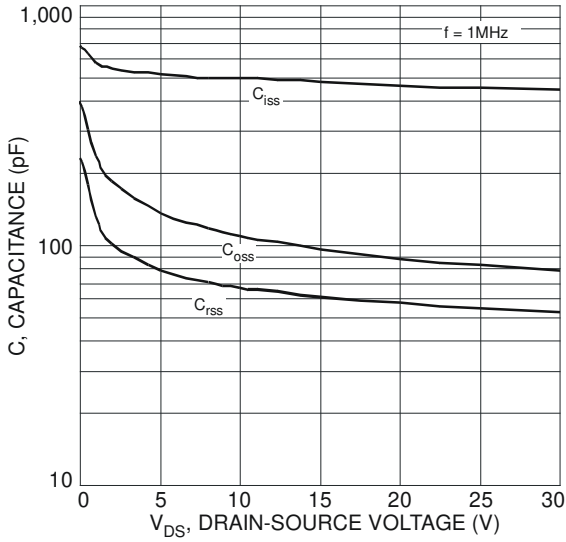


Fig. 20 Typical Total Capacitance

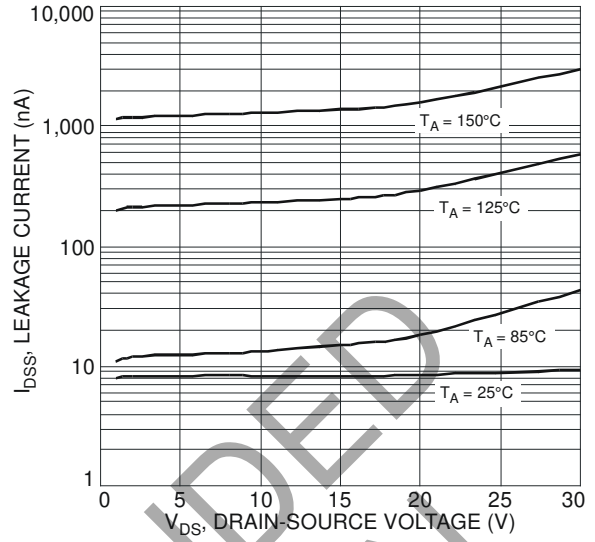


Fig. 21 Typical Leakage Current vs. Drain-Source Voltage

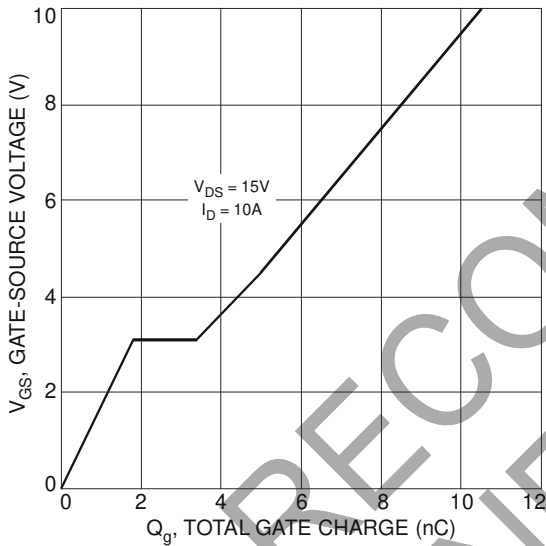


Fig. 22 Gate-Charge Characteristics

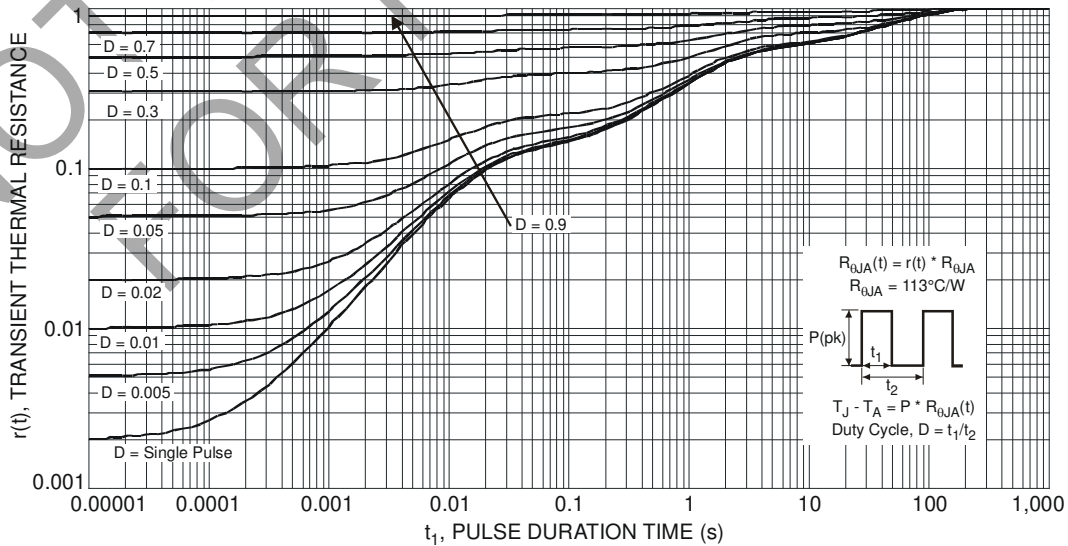
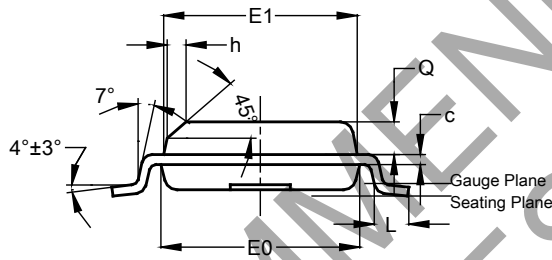
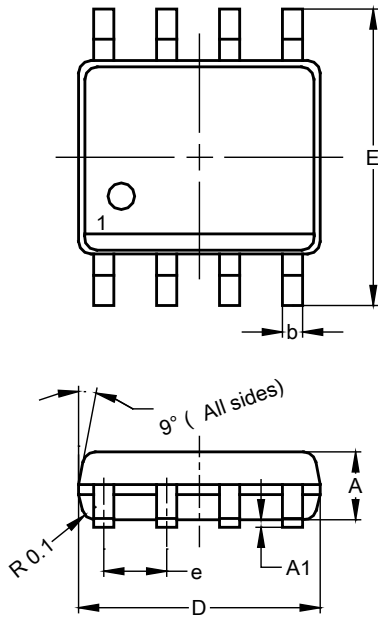


Fig. 23 Transient Thermal Response

Package Outline Dimensions

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

SO-8



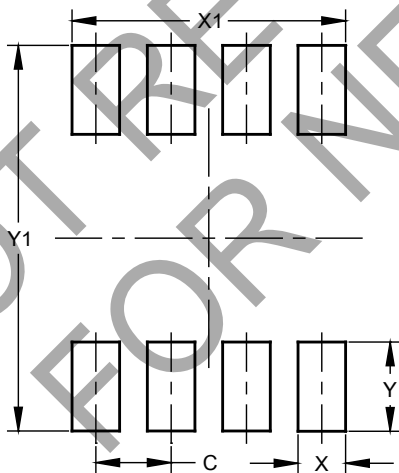
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Dim	Min	Max	Typ
A	1.40	1.50	1.45
A1	0.10	0.20	0.15
b	0.30	0.50	0.40
c	0.15	0.25	0.20
D	4.85	4.95	4.90
E	5.90	6.10	6.00
E1	3.80	3.90	3.85
E0	3.85	3.95	3.90
e	--	--	1.27
h	--	--	0.35
L	0.62	0.82	0.72
Q	0.60	0.70	0.65

All Dimensions in mm

Suggested Pad Layout

Please see <http://www.diodes.com/package-outlines.html> for the latest version.

SO-8



Dimensions	Value (in mm)
C	1.27
X	0.802
X1	4.612
Y	1.505
Y1	6.50

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2. support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in significant injury to the user.

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